



# Characterization with a β-source setup of the UFSD3.2 production manufactured at FBK

#### 16th "Trento" Workshop on Advanced Silicon Radiation Detectors, 2.18.2021

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- > FBK UFSD3.2  $\rightarrow$  3 different Gain Layer designs
- Performance of pre-rad sensors
- Performance of irradiated sensors
- ➤ V<sub>irrad</sub>(10fC) & DV(10fC)
- A study on the noise of tested sensors







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- Latest LGAD production at FBK → <u>aim at studying different</u> <u>Gain Layer (GL) designs</u>
- Tested sensors are 1.3x1.3 mm<sup>2</sup> single pads with 45 µm active thickness
- Gain implants of tested devices are enriched with carbon
  → more on M.Ferrero's talk
- Read-out with "Santa-Cruz" board



A UFSD3.2 sensor mounted on a "Santa-Cruz" board



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Goal of this talk is to discuss the characteristics of the 3 GL designs implemented in this production



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## **Gain Layer designs**





#### **Shallow** gain implant

(standard implant as previous UFSD productions)

- W3, W7



# **Gain Layer designs**





Shallow gain implant (standard implant as previous UFSD productions)

- W3, W7



**Deep CBL:** diffusion at low thermal load, narrow implant

- W10, W12, W13

**Deep CBH:** diffusion at high thermal load, broad implant

W14, W19

Deep gain implants improves the recovering power of VBias in irradiated sensors (see <u>N.Cartiglia's talk at 34th RD50 workshop</u>)

GINFN G	Wafer	Thickness	GL depth	Pga	ain dose	Carbon dose	Diffusion
	1 45 µm standard		standard	standard		А	CHBL
shallow	3	45 µm	standard	standard standard		0.8*A	CHBL
	7	<u>55 µm</u>	standard			А	CHBL
deep CBI	10	45 µm	deep		1	0.6*A	CBL
2 Pgain doses	12	45 µm	deep		2	A	CBL
2 6415011 00363	13	45 µm	deep	Q	2	0.6*A	CBL
	14	45 µm	deep	ng dos	2	A	СВН
deep CBH 2 Paain doses	15	<u>55 µm</u>	deep	creasi	2	A	СВН
2 carbon doses	18	45 µm	deep		3	А	СВН
	19	45 µm	deep	3		0.6*A	СВН







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#### are they all equivalent?









- We assess the performances of UFSD designs by looking at the collected charge and time resolution → but all these sensors have very similar performances, although they are not equal
- In the following, I will show what is the best way to discriminate between these designs









- For pre-rad sensors, the figures of merit can be the operating voltage and the steepness of the gain curve
  - $\circ$  High operating voltage  $\rightarrow$  Carriers drift velocity saturated
  - Smooth gain curve  $\rightarrow$  non uniformities between sensors affect performances less



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  - $\circ$  For a given gain/charge  $\rightarrow$  the higher Vbias, the better the time resolution is







- W19 (CBH) has very high doping, not the best pick when new
  - $\circ$  Steep gain curve  $\rightarrow$  hard to operate several sensors with same performances
  - $\circ$  Carriers drift velocity not saturated (or just close to saturation)  $\rightarrow$  can barely reach 30ps







• W 3, 7, 13, 14 in between  $\rightarrow$  work well when new, although not the best







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#### **Irradiated sensors**



#### All wafers have been irradiated at JSI TRIGA reactor $\rightarrow$ fluences: 8e14, 1.5e15, 2.5e15 n<sub>eq</sub>/cm<sup>2</sup>

c : inverse of the fluence after which the GL initial acceptor density is reduced by a factor e

Details on	UF	-SD3.2	? radiation
resistance	in	M.Fer	rero's talk

	<i>c</i> coeff. [10 <sup>-16</sup> cm <sup>2</sup> ]	Carbon dose	Pgain dose	Wafer
shallow	1,48	А	std	3
	1,91	А	std	7
deep CBL	2,16	0.6*A	1	10
	2,06	А	2	12
	1,63	0.6*A	2	13
	2,45	А	2	14
deep CBH	1,9	0.6*A	3	19







- All sensors deliver  $\geq$  10 fC up to 1.5e15 n<sub>eq</sub>/cm<sup>2</sup> (~ 5 fC at 2.5e15)
- 30 ps are reached by all tested sensors up to 1.5e15 (~40 ps at 2.5e15)













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- What do we look for in an irradiated sensor? (provided it achieves the desired resolution)
  - Operation at low VBias
  - VBias increase to compensate radiation effects as low as possible
- We can introduce two additional useful parameters to evaluate irradiated sensors:
  - $\,\circ\,$  VBias required to deliver 10fC at a given fluence  $\rightarrow$  V\_{irrad}(10fC)
  - VBias increase wrt pre-rad condition  $\rightarrow$  DV(10fC) = V<sub>irrad</sub>(10fC) V<sub>pre-rad</sub>(10fC)
- The smaller such parameters, the better the GL design







- Small V<sub>irrad</sub>(10fC) = low power consumption, safe operation of the device
- Small DV(10fC) = less affected by non-uniform irradiation → VBias shift to compensate a variation in fluence is smaller in sensors with small DV











- The higher the initial doping, the lower
  V<sub>irrad</sub>(10fC)
- W19 (deep CBH) has the lowest V<sub>irrad</sub> but poor performance when new
- W13 (deep CBL) has higher V<sub>irrad</sub> but works well when new









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- $\rightarrow$  High doping + deep implants provide the best V  $_{\rm irrad}(10fC)$









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- W13 (deep CBL) has higher V<sub>irrad</sub> but works well when new
- → High doping + deep implants provide the best  $V_{irrad}$ (10fC) → a too high doping affect the performances when new









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# **Most radiation resistant design**



- All UFSD3.2 sensors have very good radiation hardness and reach 30-40 ps up to high fluences
- V<sub>irrad</sub>(10fC) and DV(10fC) are effective figures of merit:
  - Deep and highly doped implants have the lowest  $V_{irrad}(10fC)$
  - Carbonated GL have much lower DV than not-carbonated
  - Deep implants have lower DV than shallow
  - Deep Low diffusion implants have lower DV than High diffusion ones



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- Summing up the above points → we conclude that the Carbonated deep Gain Layer with low diffusion (CBL) is the most radiation resistant design in the UFSD3.2 production







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- "Santa-Cruz" read-out board noise ~ 1.2 mV
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/m

RMS



measurements performed at -25 °C

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- There is a common trend when plotting noise vs sqrt(gain\*ln(fluence))
  - Noise ∝ sqrt(current)
  - current  $\propto$  gain\*ln(fluence)
- $\rightarrow$  noise does not depend significantly on the GL design
- *In(fluence)* reproduces better than *fluence* (backup) 1.50



 $\sqrt{Gain* \ln(Fluence)}$  [cm<sup>-1</sup>]



Z m<

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- Noise > read-out noise when: sqrt(gain\*ln(fluence)) ≥ 5 → useful indication to prevent large noise when operating the sensors



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- The UFSD3.2 production features 3 different Gain Layer (GL) designs:
  - Shallow (standard) carbonated GL
  - Deep carbonated GL with low diffusion  $\rightarrow$  "CBL"
  - Deep carbonated GL with high diffusion  $\rightarrow$  "CBH"
- Key point: the gain layer design has to be tailored to the specific application  $\rightarrow$  no design fits all needs
- Time resolution and radiation hardness are excellent for all sensors  $\rightarrow$  30-40 ps up to 2.5e15 n<sub>eq</sub>/cm<sup>2</sup>
  - <u>Need to find the figures of merit to discriminate the various designs</u>
- **Pre-rad sensors: look for operation at high voltage** (saturated fields, smooth gain curves)  $\rightarrow$  low Pgain dose
- Irradiated sensors: Deep Carbonated GL with low diffusion (CBL) are presently the most radiation resistant design
  - Operated at the lowest VBias and require the smallest increase of voltage to compensate the effects of radiations
- Very high noise appears at high gain in irradiated sensors
  - It does not depend on the GL design
  - Seems to be a threshold effect depending on the sensor gain and log of the fluence

**Thank You!** 





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- Ministero della Ricerca, Italia, FARE, R165xr8frt\_fare

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# **Torino β-source setup**



- DAQ and Analysis are fully automated
- Climate chamber
  - Can go down to -30°C with ± 0.1°C uncertainty
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- DUT + trigger Telescope, placed inside a specific structure (3d-printed) for alignment
- A trigger placed below the DUT ensures that we trigger only on MIPs
- Trigger: HPK1 1x3 mm<sup>2</sup> single pad
  - well known resolution
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- "Santa Cruz" Read-out board made by Artel
  - single channel
  - x10 amplification (+ 20dB Cividec broadband amplifier)









using In(fluence) gives a better trend

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### Weightfield2 Simulation





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